

ABSTRACT

The present invention provides a semiconductor test apparatus that can reduce the number of internal transfers of pattern files to a minimum. In the semiconductor test apparatus 11, the control unit 10 produces a pattern file use frequency table in the pattern file use frequency table memory 18, and in a set of test ⁵ in which a predetermined number of semiconductors to be tested are tested, the use frequency of the pattern files is obtained. In addition, the control unit 10 again reads out the pattern files based on the frequency of use that has been obtained, and rearrange ⁵ the pattern files in the executive memory 17. In addition, the control unit 10 deletes the pattern files in ascending order of the frequency of use when the capacity of the memory becomes insufficient.

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